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(St)	TRAD	MARIE		U.S. PATENT DOCUMENTS			2012			
*Examiner Initial		Document Number	Date	Name		Class	Subclass		g Date ropriate	
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M	AL	EP 0 923 125 A	6/16/99	EP				Yes	No	
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EXAMINER DATE CONSIDERED 11/13/13										
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										